

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 231751US267A		SERIAL NO. 10/673,507	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Eric J. STRANG, et al.		FILING DATE September 30, 2003	
				GROUP 2128			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/A.S./	AA	US 6,571,371	5/2003	Coss, et al.			
	AB	US 6,763,277	7/2004	Allen, et al.			
	AE	US 6,529,789	3/2003	Campbell, et al.			
	AD	US 6,628,809	9/2003	Rowe, et al.			
	AE	US 6,728,591	4/2004	Hussey, et al.			
	AF	US 6,774,998	8/2004	Wright, et al.			
	AG	US 2005/0016947	1/2005	Fatke, et al.			
	AH	US 2005/0010319	1/2005	Patel, et al.			
	AI	US 2003/0078738	4/2003	Wouters, et al.			
	AJ	US 2004/0078319	4/2004	Madhavan, et al.			
	AK	US 5,866,437	2/1999	Chen, et al.			
	AL	US 2004/0044513	3/2004	Kitahara, Noriaki			
	AM	US 2004/0102934	5/2004	Chang, Fang-Cheng			
/A.S./	AN	US 2003/0135302	7/2003	Hung, et al.			
FOREIGN PATENT DOCUMENTS Lined through references not provided.							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	CN 1335558 A	7/13/2002	China (with Partial English Translation)	X		
	AP	WO 03/07240 A2	1/24/2003	WIPO			X
	AQ	EP 0 718 595 A2	5/26/1996	EUROPE			X
/A.S./	AR	JP 2004-527117	9/2/2004	Japan			X
/A.S./	AS	WO 03/060779 A1	7/24/2003	WIPO			X
/A.S./	AT	JP 2005-515623	5/26/2005	JAPAN (With English Abstract)			X
/A.S./	AU	WO 03/009345 A2	1/30/2003	WIPO			X
/A.S./	AV	JP 2005-522018	7/21/2005	JAPAN (With English Abstract)			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Robert W. ATHERTON, et al. "Detailed Simulation for Semiconductor Manufacturing", Proceedings of the 1990 Winter Simulation Conference					
	AX	Angus J. MACDONALD, et al. "Integrated CAM and Process Simulation to Enhance On-Line Analysis and Control of IC Fabrication", IEEE Transactions on Semiconductor Mfg., Vol. 3, No. 2, May 1990					
	AY	Paul P. CASTRUCCI; "Emerging Paradigms in Semiconductor Manufacturing"; 1990 Int'l Semiconductor Mfg. Science Symposium: IEEE 1990					
	AZ	Yea-Huey SU, et al. "Conceptual Framework for Manufacturing Service Provisioning by Virtual Fabs"; 1998 NSC Republic Of China; 1998 Semiconductor Mfg. Technology Workshop				<input type="checkbox"/> Additional References sheet(s) attached	
Examiner		/Akash Saxena/ (03/28/2011)				Date Considered 03/28/2011	

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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/A.S./	AAA	US 6,615,097	9/2003	Ozaki, Hiroji			
	AAB	US 6,905,895	6/2005	Coss, et al.			
	AAC	US 6,812,045	11/2004	Nikoonahad, et al			
	AAD	US 6,757, 645	6/2004	Chang, et al.			
	AAE	US 6,643,616	11/2003	Granik, et al.			
	AAF	US 6,618,856	9/2003	Coburn, et al.			
	AAG	US 2004/0044513	3/2004	Kitahara, Noriaki			
	AAH	US 5,583,780	12/10/1996	Kee, et al.			
	AAI	US 2005-0071037	3/31/2005	Strang			
	AAJ	US 2005-0071035	3/31/2005	Strang			
	AAK	US 2005-0071038	3/31/2005	Strang			
	AAL	US 2005-0071036	3/31/2005	Mitrovic			
/A.S./	AAM	US 2005-0071039	3/31/2005	Mitrovic			
	AAN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/A.S./	AAO	JP 2003-17471	1/17/2003	JAPAN (With English Abstract)			X
/A.S./	AAP	WO 02/065511 A2	8/22/2002	WIPO			X
/A.S./	AAQ	JP 2004-524685	8/12/2004	JAPAN			X
/A.S./	AAR	WO 02/069063 A2	9/6/2002	WIPO			X
/A.S./	AAS	JP 2004-531878	10/14/2004	JAPAN			X
/A.S./	AAT	JP 2000-517473	12/28/2000	JAPAN (With English Abstract)			X
/A.S./	AAU	WO 03/058699 A1	7/17/2003	WIPO			X
/A.S./	AAV	JP 2005-514790	5/19/2005	JAPAN (With English Abstract)			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AAW	Chanette RASMDATTA, et al. "New approaches for Simulation of Wafer fabrication : The Use of Control Variates and Calibration Metrics" Proceedings of 2002 Winter Simulation Conference; 2002					
	AAZ	Su-shing CHEN, "AEMPES: An expert system for in-situ diagnostics and process monitoring"; Semiconductor Manufacturing Science Symposium, 1990. IEEE/SEMI International, 21-23 May 1990 Pages 119-122					
/A.S./	AAY	Heru SETYAWAN, et al. "Visualization and numerical simulation of fine particle transport in a low-pressure parallel plate chemical vapor deposition reactor", Chemical Engineering Science 57 (2002) pages 497-506					
	AAZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner /Akash Saxena/ (03/28/2011)				Date Considered 03/28/2011			

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	AAAA						
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/A.S./	AAAO	JP 2002-367875	12/20/2002	JAPAN		X	
/A.S./	AAAK	JP 2003-502771	1/21/2003	JAPAN		X	
/A.S./	AAAO	WO 02/077589 A2	10/3/2002	WIPO		X	
/A.S./	AAAR	JP 11-176906	7/2/1999	JAPAN (with English Abstract and Computer Generated Translation only)	X		
/A.S./	AAAS	WO 97/21244	6/12/1997	WIPO		X	
	AAAT						
	AAAU						
	AAAV						
	AAAW						
	AAAX						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
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	AAAZ						
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SHEET 4 OF 4

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/A.S./	AAAAA	US 6,185,472	2/6/2001	Onga, et al.			
/A.S./	AAAAB	US 7,047,095 B2	5/16/2006	Tomoyasu			
/A.S./	AAAC	US 6,587,744 B1	7/1/2003	Stoddard, et al.			
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